

1. General description

The PCA8565A is a CMOS1 Real-Time Clock (RTC) and calendar optimized for low power consumption. A programmable clock output, interrupt output, and voltage-low detector are also provided. All addresses and data are transferred serially via a two-line bidirectional I 2C-bus. Maximum bus speed is 400 kbit/s. The built-in word address register is incremented automatically after each written or read data byte.

AEC-Q100 compliant for automotive applications.

2. Features

- Provides year, month, day, weekday, hours, minutes, and seconds based on 32.768 kHz quartz crystal
- Clock operating voltage: 1.8 V to 5.5 V
- Extended operating temperature range: −40 °C to +125 °C
- Low backup current: typical 0.65 μ A at V_{DD} = 3.0 V and T_{amb} = 25 °C
- 400 kHz two-line I²C-bus interface (at $V_{DD} = 1.8$ V to 5.5 V)
- Programmable clock output for peripheral devices (32.768 kHz, 1.024 kHz, 32 Hz, and $1 Hz$
- Alarm and timer functions
- Two integrated oscillator capacitors
- Internal Power-On Reset (POR)
- I²C-bus slave address: read A3h; write A2h
- Open-drain interrupt pin
- Century flag

3. Applications

- Automotive
- Industrial
- Applications that require a wide operating temperature range

^{1.} The definition of the abbreviations and acronyms used in this data sheet can be found in [Section](#page-34-0) 18.

4. Ordering information

[1] Not to be used for new designs.

5. Marking

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6. Block diagram

7. Pinning information

7.1 Pinning

7.2 Pin description

[1] The substrate (rear side of the die) is wired to V_{SS} but should not be electrically contacted.

8. Functional description

The PCA8565A contains 16 8-bit registers with an auto-incrementing address register, an on-chip 32.768 kHz oscillator with two integrated capacitors, a frequency divider which provides the source clock for the RTC, a programmable clock output, a timer, an alarm, a voltage low detector, and a 400 kHz I²C-bus interface.

All 16 registers (see [Table](#page-5-0) 4) are designed as addressable 8-bit parallel registers although not all bits are implemented. The first two registers (memory address 00h and 01h) are used as control and/or status registers. The memory addresses 02h through 08h are used as counters for the clock function (seconds up to years counters). Address locations 09h through 0Ch contain alarm registers which define the conditions for an alarm. Address 0Dh controls the CLKOUT output frequency. 0Eh and 0Fh are the timer control and timer registers, respectively.

The seconds, minutes, hours, days, weekdays, months, years, as well as the minute alarm, hour alarm, day alarm, and weekday alarm registers are all in Binary Coded Decimal (BCD) format.

When one of the RTC registers is read, the contents of all time counters are frozen. Therefore, faulty reading of the clock and calendar during a carry condition is prevented.

8.1 CLKOUT output

A programmable square wave is available at the CLKOUT pin. Frequencies of 32.768 kHz, 1.024 kHz, 32 Hz and 1 Hz can be generated for use as a system clock, microcontroller clock, input to a charge pump, or for calibration of the oscillator. CLKOUT is an open-drain output, and if disabled it becomes high-impedance.

8.2 Register organization

Table 4. Register overview

Bit positions labelled as - are not implemented. Bit positions labelled as N should always be written with logic 0. After reset, all registers are set according to [Table](#page-20-0) 29.

8.3 Control registers

8.3.1 Register Control_status_1

[1] Default value.

[2] Bits labeled as N should always be written with logic 0.

8.3.2 Register Control_status_2

Table 6. Control_status_2 - control and status register 2 (address 01h) bit description

[1] Bits labeled as N should always be written with logic 0.

[2] Default value.

8.3.2.1 Interrupt output

Bits TF and AF: When an alarm occurs, AF is set logic 1. Similarly, at the end of a timer countdown, TF is set logic 1. These bits maintain their value until overwritten using the interface. If both timer and alarm interrupts are required in the application, the source of the interrupt can be determined by reading these bits.

To prevent one flag being overwritten while clearing another, logic AND is performed during a write access. A flag is cleared by writing logic 0 whilst a flag is not cleared by writing logic 1. Writing logic 1 will result in the flag value remaining unchanged.

The following two tables are showing an example for clearing bit AF, but leaving bit TF unaffected. The flag is cleared by a write command, therefore bits 7 to 4 and 1 to 0 must be written with their previous values. Repeatedly re-writing these bits has no influence on the functional behavior.

Table 7. AF and TF flag location in register Control_status_2

Register	D _{it} "DIL.							
			э	. .	w			
Control_status_2	$\overline{}$	$\overline{}$	-	$\overline{}$			$\overline{}$	$\overline{}$

[Table](#page-7-1) 8 shows what instruction must be sent to clear bit AF. In this example, bit TF is unaffected.

Table 8. Example to clear only AF (bit 3) in register Control_status_2

Register	Bit							
		6	э		w			'C
Control_status_2	$\overline{}$	$\overline{}$	$\overline{}$	-			$\overline{}$	$\overline{}$

Bits TIE and AIE: These bits activate or deactivate the generation of an interrupt when TF or AF is asserted, respectively. The interrupt is the logical OR of these two conditions when both AIE and TIE are set.

Countdown timer interrupts: The pulse generator for the countdown timer interrupt uses an internal clock and is dependent on the selected source clock for the countdown timer and on the countdown value n. As a consequence, the width of the interrupt pulse varies (see [Table](#page-8-0) 9).

Table 9. INT operation (bit TI_TP = 1)[\[1\]](#page-8-1)

 $[1]$ TF and $\overline{\text{INT}}$ become active simultaneously.

[2] $n =$ loaded countdown value. Timer stops when $n = 0$.

8.4 Time and date registers

The majority of the registers are coded in the BCD format to simplify application use.

8.4.1 Register VL_seconds

Table 10. VL_seconds - seconds and clock integrity status register (address 02h) bit description

[1] Start-up value.

Table 11. Seconds coded in BCD format

8.4.1.1 Voltage-low detector and clock monitor

The PCA8565A has an on-chip voltage-low detector (see $Figure 4$ $Figure 4$). When V_{DD} drops below V_{low}, bit VL in the VL_seconds register is set to indicate that the integrity of the clock information is no longer guaranteed. The VL flag can only be cleared by using the interface.

The VL flag is intended to detect the situation when V_{DD} is decreasing slowly, for example under battery operation. Should the oscillator stop or V_{DD} reach V_{low} before power is re-asserted, then the VL flag is set. This will indicate that the time may be corrupted.

8.4.2 Register Minutes

Table 12. Minutes - minutes register (address 03h) bit description

8.4.3 Register Hours

8.4.4 Register Days

Table 14. Days - days register (address 05h) bit description

[1] The PCA8565A compensates for leap years by adding a 29th day to February if the year counter contains a value which is exactly divisible by 4, including the year 00.

8.4.5 Register Weekdays

Table 15. Weekdays - weekdays register (address 06h) bit description

Table 16. Weekday assignments

[1] Definition may be re-assigned by the user.

8.4.6 Register Century_months

Table 17. Century_months - century flag and months register (address 07h) bit description

[1] This bit may be re-assigned by the user.

[2] This bit is toggled when the register Years overflows from 99 to 00.

Table 18. Month assignments in BCD format

8.4.7 Register Years

8.5 Setting and reading the time

[Figure](#page-12-0) 5 shows the data flow and data dependencies starting from the 1 Hz clock tick.

During read/write operations, the time counting circuits (memory locations 02h through 08h) are blocked.

This prevents

- **•** Faulty reading of the clock and calendar during a carry condition
- **•** Incrementing the time registers, during the read cycle

After this read/write access is completed, the time circuit is released again and any pending request to increment the time counters that occurred during the read access is serviced. A maximum of 1 request can be stored; therefore, all accesses must be completed within 1 second (see [Figure](#page-13-0) 6).

As a consequence of this method, it is very important to make a read or write access in one go, that is, setting or reading seconds through to years should be made in one single access. Failing to comply with this method could result in the time becoming corrupted.

As an example, if the time (seconds through to hours) is set in one access and then in a second access the date is set, it is possible that the time may increment between the two accesses. A similar problem exists when reading. A roll over may occur between reads thus giving the minutes from one moment and the hours from the next.

Recommended method for reading the time:

- 1. Send a START condition and the slave address for write (A2h).
- 2. Set the address pointer to 2 (VL_seconds) by sending 02h.
- 3. Send a RESTART condition or STOP followed by START.
- 4. Send the slave address for read (A3h).
- 5. Read VL seconds.
- 6. Read Minutes.
- 7. Read Hours.
- 8. Read Days.
- 9. Read Weekdays.
- 10. Read Century_months.
- 11. Read Years.
- 12. Send a STOP condition.

8.6 Alarm registers

8.6.1 Register Minute_alarm

[1] Default value.

8.6.2 Register Hour_alarm

Table 21. Hour_alarm - hour alarm register (address 0Ah) bit description

[1] Default value.

8.6.3 Register Day_alarm

Table 22. Day_alarm - day alarm register (address 0Bh) bit description

[1] Default value.

8.6.4 Register Weekday_alarm

Table 23. Weekday_alarm - weekday alarm register (address 0Ch) bit description

[1] Default value.

8.6.5 Alarm flag

By clearing the MSB of one or more of the alarm registers, $AE \times (A \text{larm Enable})$, the corresponding alarm condition(s) are active. When an alarm occurs, AF is set logic 1. The asserted AF can be used to generate an interrupt $(\overline{\text{INT}})$. The AF is cleared by using the interface.

The registers at addresses 09h through 0Ch contain alarm information. When one or more of these registers is loaded with minute, hour, day or weekday, and its corresponding Alarm Enable bit ($AE\ x$) is logic 0, then that information is compared with the current minute, hour, day, and weekday. When all enabled comparisons first match, the Alarm Flag (AF in register Control_status_2) is set logic 1.

The generation of interrupts from the alarm function is controlled via bit AIE. If bit AIE is enabled, the $\overline{\text{INT}}$ pin follows the condition of bit AF. AF will remain set until cleared by using the interface. Once AF has been cleared, it will only be set again when the time increments to match the alarm condition once more. Alarm registers which have their AE_x bit at logic 1 are ignored.

8.7 Register CLKOUT_control and clock output

Frequencies of 32.768 kHz (default), 1.024 kHz, 32 Hz, and 1 Hz can be generated for use as a system clock, microcontroller clock, input to a charge pump, or for calibration of the oscillator. To enable pin CLKOUT pin CLKOE must be set HIGH. When disabled, CLKOUT is high-impedance.

Bit	Symbol	Value	Description
7 to $2 -$		-	unused
	1 to 0 FD[1:0]		frequency output at pin CLKOUT
		$00^{[1]}$	32.768 kHz
		01	1.024 kHz
		10	32 Hz
		11	1 Hz

Table 24. CLKOUT_control - CLKOUT control register (address 0Dh) bit description

[1] Default value.

8.8 Timer function

The 8-bit countdown timer at address 0Fh is controlled by the timer control register at address 0Eh. The timer control register determines one of 4 source clock frequencies for the timer (4.096 kHz, 64 Hz, 1 Hz, or $\frac{1}{60}$ Hz) and enables or disables the timer. The timer counts down from a software-loaded 8-bit binary value. At the end of every countdown, the timer sets the Timer Flag (TF) in the register Control_status_2. The TF may only be cleared by software. The asserted TF can be used to generate an interrupt (on pin $\overline{\text{INT}}$). The interrupt may be generated as a pulsed signal every countdown period or as a permanently active signal which follows the state of TF. Bit TI_TP is used to control this mode selection. When reading the timer, the current countdown value is returned.

8.8.1 Register Timer_control

Table 25. Timer_control - timer control register (address 0Eh) bit description

[1] Default value.

[2] These bits determine the source clock for the countdown timer; when not in use, TD[1:0] should be set to $\frac{1}{60}$ Hz for power saving.

8.8.2 Register Timer

Table 27. Timer register bits value range

The timer register is an 8-bit binary countdown timer. It is enabled or disabled via the Timer_control register. The source clock for the timer is also selected by the Timer_control register. Other timer properties such as single or periodic interrupt generation are controlled via the register Control_status_2 (address 01h).

For accurate read back of the count down value, it is recommended to read the register twice and check for consistent results, since it is not possible to freeze the countdown timer counter during read back.

8.9 EXT_CLK test mode

A test mode is available which allows for on-board testing. In such a mode it is possible to set up test conditions and control the operation of the RTC.

The test mode is entered by setting bit TEST1 in register Control_status_1. Then pin CLKOUT becomes an input. The test mode replaces the internal 64 Hz signal with the signal applied to pin CLKOUT. Every 64 positive edges applied to pin CLKOUT will then generate an increment of one second.

The signal applied to pin CLKOUT should have a minimum pulse width of 300 ns and a maximum period of 1000 ns. The internal 64 Hz clock, now sourced from CLKOUT, is divided down to 1 Hz by a 2^6 divide chain called a prescaler. The prescaler can be set into a known state by using the bit STOP. When the STOP bit is set, the prescaler is reset to logic 0 (STOP must be cleared before the prescaler can operate again).

From a STOP condition, the first 1 second increment will take place after 32 positive edges on pin CLKOUT. Thereafter, every 64 positive edges will cause a one-second increment.

Remark: Entry into EXT_CLK test mode is not synchronized to the internal 64 Hz clock. When entering the test mode, no assumption as to the state of the prescaler can be made.

Operation example:

- 1. Set EXT CLK test mode (Control status 1, bit TEST1 = 1).
- 2. Set bit STOP (Control_status_1, bit STOP = 1).
- 3. Clear bit STOP (Control status 1, bit STOP = 0).
- 4. Set time registers to desired value.
- 5. Apply 32 clock pulses to pin CLKOUT.
- 6. Read time registers to see the first change.
- 7. Apply 64 clock pulses to pin CLKOUT.
- 8. Read time registers to see the second change.

Repeat steps 7 and 8 for additional increments.

8.10 STOP bit function

The function of the STOP bit is to allow for accurate starting of the time circuits. The STOP bit function will cause the upper part of the prescaler (F_2 to F_{14}) to be held in reset and thus no 1 Hz ticks will be generated (see [Figure](#page-18-1) 8). The time circuits can then be set and will not increment until the STOP bit is released (see [Figure](#page-18-2) 9 and [Table](#page-19-0) 28).

The STOP bit function will not affect the output of 32.768 kHz on CLKOUT, but will stop the generation of 1.024 kHz, 32 Hz, and 1 Hz.

The lower two stages of the prescaler (F_0 and F_1) are not reset; and because the I²C-bus is asynchronous to the crystal oscillator, the accuracy of re-starting the time circuits will be between zero and one 8.192 kHz cycle (see [Figure](#page-18-2) 9).

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Table 28. First increment of time circuits after STOP bit release

[1] F_0 is clocked at 32.768 kHz.

The first increment of the time circuits is between 0.507813 s and 0.507935 s after STOP bit is released. The uncertainty is caused by the prescaler bits F_0 and F_1 not being reset (see [Table](#page-19-0) 28) and the unknown state of the 32 kHz clock.

8.11 Reset

The PCA8565A includes an internal reset circuit which is active whenever the oscillator is stopped. In the reset state the I²C-bus logic is initialized including the address pointer and all registers are set according to [Table](#page-20-0) 29. I²C-bus communication is not possible during reset.

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[1] Registers marked 'x' are undefined at power-up and unchanged by subsequent resets.

8.11.1 Power-On Reset (POR) override

Table 29. Register reset value[s\[1\]](#page-20-2)

The POR duration is directly related to the crystal oscillator start-up time. Due to the long start-up times experienced by these types of circuits, a mechanism has been built in to disable the POR and hence speed up on-board test of the device. The setting of this mode requires that the I2C-bus pins, SDA and SCL, be toggled in a specific order as shown in [Figure](#page-20-3) 10. All timings are required minimums.

Once the override mode has been entered, the device immediately stops, being reset, and normal operation may commence, i.e., entry into the EXT_CLK test mode via I²C-bus access. The override mode may be cleared by writing logic 0 to TESTC. TESTC must be set logic 1 before re-entry into the override mode is possible. Setting TESTC logic 0 during normal operation has no effect, except to prevent entry into the POR override mode.

9. Characteristics of the I2C-bus

The I2C-bus is for bidirectional, two-line communication between different ICs or modules. The two lines are a Serial Data Line (SDA) and a Serial Clock Line (SCL). Both lines must be connected to a positive supply via a pull-up resistor. Data transfer may be initiated only when the bus is not busy.

9.1 Bit transfer

One data bit is transferred during each clock pulse. The data on the SDA line must remain stable during the HIGH period of the clock pulse, as changes in the data line at this time will be interpreted as a control signal (see [Figure](#page-21-0) 11).

9.2 START and STOP conditions

Both data and clock lines remain HIGH when the bus is not busy. A HIGH-to-LOW transition of the data line, while the clock is HIGH, is defined as the START condition (S). A LOW-to-HIGH transition of the data line, while the clock is HIGH, is defined as the STOP condition (P); see [Figure](#page-21-1) 12.

9.3 System configuration

A device generating a message is a transmitter; a device receiving a message is a receiver. The device that controls the message is the master; and the devices which are controlled by the master are the slaves (see [Figure](#page-22-0) 13).

9.4 Acknowledge

The number of data bytes transferred between the START and STOP conditions from transmitter to receiver is unlimited. Each byte of eight bits is followed by an acknowledge cycle.

- **•** A slave receiver, which is addressed, must generate an acknowledge after the reception of each byte.
- **•** Also a master receiver must generate an acknowledge after the reception of each byte that has been clocked out of the slave transmitter.
- **•** The device that acknowledges must pull-down the SDA line during the acknowledge clock pulse, so that the SDA line is stable LOW during the HIGH period of the acknowledge related clock pulse (set-up and hold times must be taken into consideration).
- **•** A master receiver must signal an end of data to the transmitter by not generating an acknowledge on the last byte that has been clocked out of the slave. In this event the transmitter must leave the data line HIGH to enable the master to generate a STOP condition.

Acknowledgement on the I²C-bus is shown in [Figure](#page-22-1) 14.

9.5 I2C-bus protocol

9.5.1 Addressing

Before any data is transmitted on the I²C-bus, the device which should respond is addressed first. The addressing is always carried out with the first byte transmitted after the start procedure.

The PCA8565A acts as a slave receiver or slave transmitter. Therefore, the clock signal SCL is only an input signal, but the data signal SDA is a bidirectional line.

Two slave addresses are reserved for the PCA8565A:

Read: A3h (10100011)

Write: A2h (10100010)

The PCA8565A slave address is shown in [Figure](#page-23-0) 15.

9.5.2 Clock and calendar READ or WRITE cycles

The I2C-bus configuration for the different PCA8565A READ and WRITE cycles is shown in [Figure](#page-23-1) 16, [Figure](#page-24-0) 17, and [Figure](#page-24-1) 18. The word address is a 4-bit value that defines which register is to be accessed next. The upper four bits of the word address are not used.

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Fig 17. Master reads after setting word address (write word address; READ data)

9.5.3 Interface watchdog timer

During read/write operations, the time counting circuits are frozen. To prevent a situation where the accessing device becomes locked and does not clear the interface, the PCA8565A has a built in watchdog timer. Should the interface be active for more than 1 s from the time a valid slave address is transmitted, then the PCA8565A will automatically clear the interface and allow the time counting circuits to continue counting.

The watchdog is implemented to prevent the excessive loss of time due to interface access failure e.g. if main power is removed from a battery backed-up system during an interface access.

Each time the watchdog period is exceeded, 1 s will be lost from the time counters. The watchdog will trigger between 1 s and 2 s after receiving a valid slave address.

10. Internal circuitry

11. Limiting values

[1] Pass level; Human Body Model (HBM) according to [Ref. 4 "JESD22-A114"](#page-35-0).

[2] Pass level; Machine Model (MM), according to [Ref. 5 "JESD22-A115".](#page-35-1)

[3] Pass level; latch-up testing, according to [Ref. 7 "JESD78"](#page-35-2) at maximum ambient temperature $(T_{amb(max)} = +125 \degree C$).

[4] According to the NXP store and transport requirements (see [Ref. 9 "NX3-00092"](#page-35-3)) the devices have to be stored at a temperature of +8 °C to +45 °C and a humidity of 25% to 75 %. For long term storage products deviant conditions are described in that document.

12. Static characteristics

Table 31. Static characteristics

 V_{DD} = 1.8 V to 5.5 V; V_{SS} = 0 V; T_{amb} = -40 °C to +125 °C; f_{osc} = 32.768 kHz; quartz R_s = 40 kQ; C_L = 8 pF; unless otherwise specified.

Table 31. Static characteristics …continued

 V_{DD} = 1.8 V to 5.5 V; V_{SS} = 0 V; T_{amb} = -40 °C to +125 °C; f_{osc} = 32.768 kHz; quartz R_s = 40 kΩ; C_L = 8 pF; unless otherwise specified.

[1] Timer source clock = $\frac{1}{60}$ Hz, level of pins SCL and SDA is V_{DD} or V_{SS}.

[2] Worst case is at high temperature and high supply voltage.

[3] Tested on sample basis.

13. Dynamic characteristics

Table 32. Dynamic characteristics

 V_{DD} = 1.8 V to 5.5 V; V_{SS} = 0 V; T_{amb} = -40 °C to + 125 °C; f_{osc} = 32.768 kHz; quartz R_s = 40 kΩ; C_L = 8 pF; unless otherwise specified.

[1] Integrated load capacitance, C_{L(itg)}, is a calculation of C_{OSCI} and C_{OSCO} in series: $C_{L(itg)} = \frac{(C_{OSCI} \cdot C_{OSCO})}{(C_{OSCI} + C_{OSCO})}$.

[2] Unspecified for $f_{CLKOUT} = 32.768$ kHz.

[3] All timing values are valid within the operating supply voltage range at ambient temperature and referenced to V_{IL} and V_{IH} with an input voltage swing of V_{SS} to V_{DD} .

[4] A detailed description of the I²C-bus specification is given in [Ref. 10 "UM10204".](#page-35-4)

[5] I²C-bus access time between two starts or between a start and a stop condition to this device must be less than one second.

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14. Application information

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15. Bare die outline

Fig 22. Bare die outline

Table 33. Pin description

All x/y coordinates represent the position of the center of each pad with respect to the center $(x/y = 0)$ of the chip; see [Figure](#page-31-0) 22.

Table 34. Alignment mark description

All x/y coordinates represent the position of the REF point (see [Figure](#page-32-0) 23) with respect to the center $(x/y = 0)$ of the chip; see [Figure](#page-31-0) 22.

16. Handling information

All input and output pins are protected against ElectroStatic Discharge (ESD) under normal handling. When handling Metal-Oxide Semiconductor (MOS) devices ensure that all normal precautions are taken as described in JESD625-A, IEC 61340-5 or equivalent standards.

17. Packing information

18. Abbreviations

19. References

- **[1] AN10706 —** Handling bare die
- **[2] IEC 60134 —** Rating systems for electronic tubes and valves and analogous semiconductor devices
- **[3] IEC 61340-5 —** Protection of electronic devices from electrostatic phenomena
- **[4] JESD22-A114 —** Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)
- **[5] JESD22-A115 —** Electrostatic Discharge (ESD) Sensitivity Testing Machine Model (MM)
- **[6] JESD22-C101 —** Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components
- **[7] JESD78 —** IC Latch-Up Test
- **[8] JESD625-A —** Requirements for Handling Electrostatic-Discharge-Sensitive (ESDS) Devices
- **[9] NX3-00092 —** NXP store and transport requirements
- **[10] UM10204 —** I 2C-bus specification and user manual

20. Revision history

21. Legal information

21.1 Data sheet status

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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All die sales are conditioned upon and subject to the customer entering into a written die sale agreement with NXP Semiconductors through its legal department.

21.4 Trademarks

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22. Contact information

For more information, please visit: **http://www.nxp.com**

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Real-time clock/calendar

23. Contents

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

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